

<b>Notice of References Cited</b>	Application/Control No. 10/624,521	Applicant(s)/Patent Under Reexamination HA ET AL.	
	Examiner FEBEN HAILE	Art Unit 2616	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,657,964	12-2003	Kohzuki et al.	370/236.1
*	B	US-6,791,943	09-2004	Reynolds, Scott B.	370/232
*	C	US-7,209,443	04-2007	Mukai et al.	370/235
*	D	US-6,687,225	02-2004	Kawarai et al.	370/230.1
*	E	US-5,940,375	08-1999	Soumiya et al.	370/249
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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